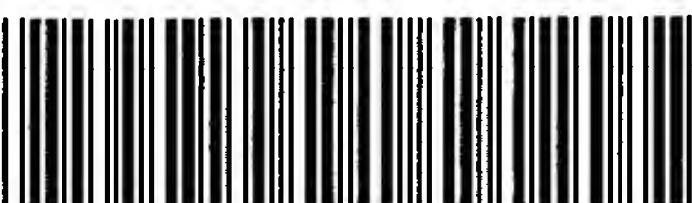


Search Notes**Application/Control No.**

10/806,045

Examiner

Phuong Huynh

Applicant(s)/Patent under Reexamination

KOURI ET AL.

Art Unit

2857

SEARCHED

Class	Subclass	Date	Examiner
702	76	8/5/2005	PH
Updated	Above	5/1/2006	PH
Updated	Above	8/23/2006	PH
356	446, 625	8/23/2006	PH
702	1	8/23/2006	PH
702	66	8/23/2006	PH
702	67	8/23/2006	PH
702	127,134	8/23/2006	PH
Updated	Above	12/15/2006	PH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
702	76	5/1/2006	PH
Updated	Above	8/23/2006	PH
Updated	Above	12/15/2006	PH

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
356/32,34,300,303,450,451,432,445,448,213,228,947,253,254,255,226,340,239,237,222 with text Lippmann-Schwinger	8/5/2005	PH
Consulted with Michael Nghiem for search area as well as double patterning checking	8/2/2005	PH
Consulted with Marc Hoff for searching area: Optics	8/4/2005	PH
Talked with Sang Nguyen for optics search strategy	8/4/2005	PH
Google and IEEE searching (text: Lippmann-Schwinger equation solution; Inverse scattering solution; approximation method;	8/1/2005	PH
Google and IEEE searching (text: iterative solution, inverse scattering problems	8/1/2005	PH
Consulted with Primary Examiner Richard Rosenberger: Cross and search 356/446 and 625	4/27/2006	PH
Inventor search Edan and East with text (See East for details and dates)		PH

Search Notes (continued)



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Reexamination**

KOURI ET AL.

Art Unit

2857

SEARCHED

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

DATE	EXMR
702/1, 66,67,76, 127, 134; 356/446,625 with text	8/23/2006
Assignment Data (eDan)	8/23/2006
Consulted with SPE. Marc S. Hoff	9/1/2006
702/1, 66,67,76, 127, 134; 356/446,625 with text	12/15/2006

INTERFERENCE SEARCHED

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner